

Search Notes

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Examiner

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LEE ET AL.

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SEARCHED

Class	Subclass	Date	Examiner
708	523	9/21/2005	MAI

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor search Double Patenting Check Data Bases Search (see search history printout(s) printout)	9/21/2005	MAI